

Program

10 July 2011

14:00 – 16:00

LAYTEC 15th IN-SITU SEMINAR

Glasgow, Scottish Exhibition and Conference Centre (SECC)
Leven Room

Time	Speaker	Topic
13:00 – 14:00		Lunch
14:00 – 14:10	Dr. Thomas Zettler LayTec	Welcoming words
14:10 – 14:25	Dr. Anatol Lochmann LayTec	Current products for III-N MOCVD: measurement principles and applications
14:25 – 14:40	Prof. Misaichi Takeuchi Ritsumeikan University, Japan	Highly emissive deep UV LEDs grown by commercialized MOCVD with LayTec sensors.
14:40 – 14:55	Dr. Tim Wernicke TU Berlin	Curvature and reflectance monitoring of UV LEDs
14:55 – 15:05	Dr. Kolja Haberland LayTec	New products and developments
15:05 – 15:20	Dr. Frank Brunner FBH Berlin	EpiCurve [®] AR and Pyro400 measurements on GaN layers
15:20 – 15:35	Christoph Berger OvG University, Magdeburg	Curvature measurements during GaN growth on Si
15:35 – 15:50	Dr. Kolja Haberland LayTec	EpiNet 2.0 – next generation software
15:50 – 16:00		Discussion and Closing Remarks